

ABSTRACT

The invention relates to the characterization of tunable lasers. One particular method of characterizing a semiconductor laser is useful for a laser
5 having first and second tuning sections controlled by respective first and second tuning currents. The method includes measuring power output from the laser as a function of the first and second tuning currents, and creating an image of power as a function of the two tuning currents. The image is analyzed to determine different modes, each mode corresponding to limited ranges of
10 the first and second tuning currents. A preferred combination of the first and second tuning currents is determined for each mode and an acceptable operating region is defined for each mode.

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